

# Search Notes



Application/Control No.

09/767,730

Examiner

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Applicant(s)/Patent under Reexamination

BUCKLEY ET AL.

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705		updating 5/06	Zn
	1		
	7		
	8		
	9		
	10		
706	45		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	5/06	Zn
1. Patent 2. PG Pub		
II FOREIGN		
1. EPO 2. JPO 3. Derwent		